

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Swee-Ann Teo et al.                      Art Unit : Unknown  
Serial No. : Unassigned                                  Examiner : Unknown  
Filed :  
Title : SIGMA DELTA MODULATED PHASE LOCK LOOP WITH PHASE  
INTERPOLATION

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

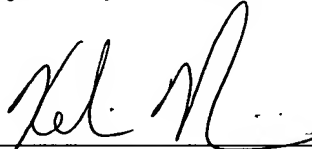
INFORMATION DISCLOSURE STATEMENT

Applicant submits the references listed on the attached form PTO-1449.

This statement is being filed with the application. Accordingly, only copies of foreign patent documents and non-patent literature are enclosed. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 12-15-03

  
\_\_\_\_\_  
Kelvin M. Vivian  
Reg. No. 53,727

Eric B. Janofsky  
General Patent Counsel  
Marvell Semiconductor, Inc.  
700 First Street, Mail Stop 509  
Sunnyvale, CA 94089  
Customer No. 23624

50189601.doc

CERTIFICATE OF MAILING BY EXPRESS MAIL

Express Mail Label No. EV 321 387 858 US

December 15, 2003  
Date of Deposit

Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. <b>MP0359</b>	Application No. <b>Unassigned</b>
	Applicant <b>Swee-Ann Teo et al.</b>		
	Filing Date <b>Herewith</b>	Group Art Unit <b>Unknown</b>	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication / Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,031,426	02/29/2000	Yechuri			
	AB	6,420,940	07/16/2002	Minnis et al.			
	AC	6,509,773	01/21/2003	Buchwald et al.			
	AD	6,542,013	04/01/2003	Volk et al.			
	AE	US/2002/0163389A1	11/07/2002	Jun			
	AF	US/2003/0108143A1	06/12/2003	Han et al.			
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	WO 00002316 A1	01/13/2000	WIPO				
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	